

## Quad 2-Input Register

### Features

- Function, pinout and drive compatible with FCT and F logic
- FCT-C speed at 6.1 ns max. (Com'l)
- FCT-A speed at 7.0 ns max. (Com'l)
- Reduced  $V_{OH}$  (typically = 3.3V) versions of equivalent FCT functions
- Edge-rate control circuitry for significantly improved noise characteristics
- Power-off disable feature
- Matched rise and fall times

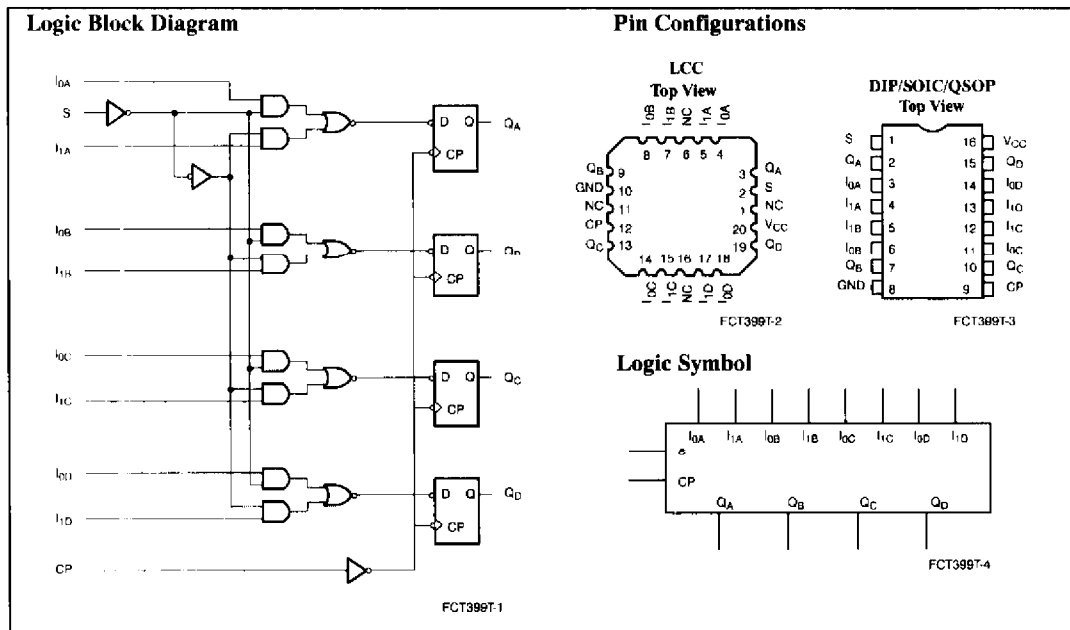
- ESD > 2000V
- Fully compatible with TTL input and output logic levels
- Sink current 64 mA (Com'l), 32 mA (Mil)
- Source current 32 mA (Com'l), 12 mA (Mil)

### Functional Description

The FCT399T is a high-speed quad dual-port register that selects four bits of data from either of two sources (Ports) under control of a common Select input

(S). The selected data is transferred to a 4-bit output register synchronous with the LOW-to-HIGH transition of the Clock input (CP). The 4-bit D-type output register is fully edge-triggered. The Data inputs ( $I_{0X}$ ,  $I_{1X}$ ) and Select input (S) must be stable only one set-up time prior to, and hold time after, the LOW-to-HIGH transition of the Clock input for predictable operation. The FCT399T offers true outputs.

The outputs are designed with a power-off disable feature to allow for live insertion of boards.



### Pin Description

Name	Description
S	Common Select Input
CP	Clock Pulse Input (Active Rising Edge)
$I_0$	Data Inputs from Source 0
$I_1$	Data Inputs from Source 1
Q	Register True Outputs

### Function Table<sup>(1)</sup>

Inputs			Outputs
S	$I_0$	$I_1$	Q
l	l	X	L
l	h	X	H
h	X	l	L
h	X	h	H

#### Note:

1. H = HIGH Voltage Level  
h = HIGH Voltage Level one set-up time prior to the LOW-to-HIGH Clock Transition  
L = LOW Voltage Level  
l = LOW Voltage Level one set-up time prior to the LOW-to-HIGH Clock Transition  
X = Don't Care



**Maximum Ratings<sup>(2, 3)</sup>**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... -65°C to +150°C  
 Ambient Temperature with Power Applied ..... -65°C to +135°C  
 Supply Voltage to Ground Potential ..... -0.5V to +7.0V  
 DC Input Voltage ..... -0.5V to +7.0V  
 DC Output Voltage ..... 0.5V to +7.0V  
 DC Output Current (Maximum Sink Current/Pin) ..... 120 mA  
 Power Dissipation ..... 0.5W

Static Discharge Voltage ..... >2001V  
 (per MIL-STD-883, Method 3015)

**Operating Range**

Range	Range	Ambient Temperature	V <sub>CC</sub>
Commercial	CT	0°C to +70°C	5V ± 5%
Commercial	T, AT	40°C to +85°C	5V ± 5%
Military <sup>(4)</sup>	All	-55°C to +125°C	5V ± 10%

**Electrical Characteristics Over the Operating Range**

Parameter	Description	Test Conditions	Min.	Typ. <sup>(5)</sup>	Max.	Unit
V <sub>OHI</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OHI</sub> = -32 mA, Com'l	2.0			V
		V <sub>CC</sub> = Min., I <sub>OHI</sub> = -15 mA, Com'l	2.4	3.3		V
		V <sub>CC</sub> = Min., I <sub>OHI</sub> = -12 mA, Mil	2.4	3.3		V
V <sub>OIL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OIL</sub> = 64 mA, Com'l		0.3	0.55	V
		V <sub>CC</sub> = Min., I <sub>OIL</sub> = 32 mA, Mil		0.3	0.55	V
V <sub>IHI</sub>	Input HIGH Voltage		2.0			V
V <sub>ILI</sub>	Input LOW Voltage				0.8	V
V <sub>HY</sub>	Hysteresis <sup>(6)</sup>	All inputs		0.2		V
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min., I <sub>IN</sub> = -18 mA		-0.7	-1.2	V
I <sub>H</sub>	Input HIGH Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = V <sub>CC</sub>			5	µA
I <sub>IHI</sub>	Input HIGH Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = 2.7V			±1	µA
I <sub>LI</sub>	Input LOW Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = 0.5V			±1	µA
I <sub>OS</sub>	Output Short Circuit Current <sup>(7)</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = 0.0V	-60	-120	-225	mA
I <sub>ON</sub>	Power-Off Disable	V <sub>CC</sub> = 0V, V <sub>OUT</sub> = 4.5V			±1	µA

**Capacitance<sup>(6)</sup>**

Parameter	Description	Typ. <sup>(5)</sup>	Max.	Unit
C <sub>IN</sub>	Input Capacitance	5	10	pF
C <sub>OUT</sub>	Output Capacitance	9	12	pF

**Notes:**

- Unless otherwise noted, these limits are over the operating free-air temperature range.
- Unused inputs must always be connected to an appropriate logic voltage level, preferably either V<sub>CC</sub> or ground.
- T<sub>A</sub> is the "instant on" case temperature.
- Typical values are at V<sub>CC</sub> = 5.0V, T<sub>A</sub> = +25°C ambient.
- This parameter is guaranteed but not tested.
- Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques is preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

**Power Supply Characteristics**

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit
$I_{CC}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} \leq 0.2V,$ $V_{IN} \geq V_{CC} - 0.2V$	0.1	0.2	mA
$\Delta I_{CC}$	Quiescent Power Supply Current (TTL inputs)	$V_{CC} = \text{Max.}, V_{IN} = 3.4V$ <sup>[8]</sup> $f_1 = 0, \text{Outputs Open}$	0.5	2.0	mA
$I_{CC(D)}$	Dynamic Power Supply Current <sup>[9]</sup>	$V_{CC} = \text{Max.}, \text{One Input Toggling},$ $50\% \text{ Duty Cycle, Outputs Open},$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	0.06	0.12	mA/ MHz
$I_C$	Total Power Supply Current <sup>[10]</sup>	$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open},$ $\text{One Input Toggling at } f_1 = 5 \text{ MHz},$ $S = \text{Steady State}$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	0.7	1.4	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open},$ $\text{One Input Toggling at } f_1 = 5 \text{ MHz},$ $S = \text{Steady State}$ $V_{IN} = 3.4V \text{ or } V_{IN} = \text{GND}$	1.2	3.4	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open},$ $\text{Four Inputs Toggling at } f_1 = 5 \text{ MHz},$ $S = \text{Steady State}$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	1.6	3.2 <sup>[11]</sup>	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open},$ $\text{Four Inputs Toggling at } f_1 = 5 \text{ MHz},$ $S = \text{Steady State}$ $V_{IN} = 3.4V \text{ or } V_{IN} = \text{GND}$	2.9	8.2 <sup>[11]</sup>	mA

**Notes:**

8. Per TTL driven input ( $V_{IN} = 3.4V$ ); all other inputs at  $V_{CC}$  or GND.

9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

10.  $I_C = I_{\text{QUIESCIENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$

$I_C = I_{CC} + \Delta I_{CC} D_{H1} N_1 + I_{CC(D)} (f_0/2 + f_1 N_1)$

$I_{CC} = \text{Quiescent Current with CMOS input levels}$

$\Delta I_{CC} = \text{Power Supply Current for a TTL HIGH input}$   
( $V_{IN} = 3.4V$ )

$D_{H1} = \text{Duty Cycle for TTL inputs HIGH}$

$N_1 = \text{Number of TTL inputs at } D_{H1}$

$I_{CC(D)} = \text{Dynamic Current caused by an input transition pair}$   
(HLH or LHL)

$f_0 = \text{Clock frequency for registered devices, otherwise zero}$

$f_1 = \text{Input signal frequency}$

$N_1 = \text{Number of inputs changing at } f_1$

All currents are in milliamps and all frequencies are in megahertz.

11. Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.



**Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
6.1	CY74FCT399CTPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT399CTQC	Q1	16-Lead (150-Mil) QSOP	
	CY74FCT399CTSOC	S1	16-Lead (300-Mil) Molded SOIC	
6.6	CY54FCT399CTDMB	D2	16-Lead (300-Mil) CerDIP	Military
	CY54FCT399CTLMB	L61	20-Pin Square Leadless Chip Carrier	
7.0	CY74FCT399ATPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT399ATQC	Q1	16-Lead (150-Mil) QSOP	
	CY74FCT399ATSOC	S1	16-Lead (300-Mil) Molded SOIC	
7.5	CY54FCT399ATDMB	D2	16-Lead (300-Mil) CerDIP	Military
	CY54FCT399ATLMB	L61	20-Pin Square Leadless Chip Carrier	
10.0	CY74FCT399TPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT399TQC	Q1	16-Lead (150-Mil) QSOP	
	CY74FCT399TSOC	S1	16-Lead (300-Mil) Molded SOIC	
11.5	CY54FCT399TDMB	D2	16-Lead (300-Mil) CerDIP	Military
	CY54FCT399TLMB	L61	20-Pin Square Leadless Chip Carrier	

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6.1	CY74FCT399CTPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
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	CY74FCT399CTSOC	S1	16-Lead (300-Mil) Molded SOIC	
6.6	CY54FCT399CTDMB	D2	16-Lead (300-Mil) CerDIP	Military
	CY54FCT399CTLMB	L61	20-Pin Square Leadless Chip Carrier	
7.0	CY74FCT399ATPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT399ATQC	Q1	16-Lead (150-Mil) QSOP	
	CY74FCT399ATSOC	S1	16-Lead (300-Mil) Molded SOIC	
7.5	CY54FCT399ATDMB	D2	16-Lead (300-Mil) CerDIP	Military
	CY54FCT399ATLMB	L61	20-Pin Square Leadless Chip Carrier	
10.0	CY74FCT399TPC	P1	16-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT399TQC	Q1	16-Lead (150-Mil) QSOP	
	CY74FCT399TSOC	S1	16-Lead (300-Mil) Molded SOIC	
11.5	CY54FCT399TDMB	D2	16-Lead (300-Mil) CerDIP	Military
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